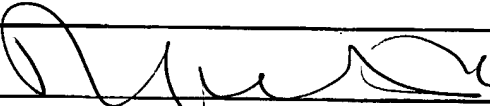
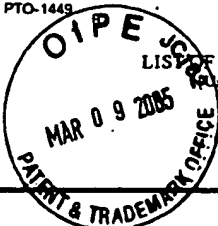
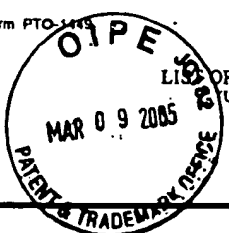
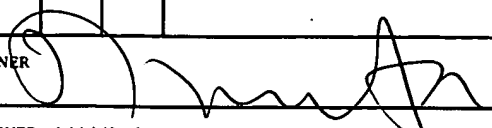
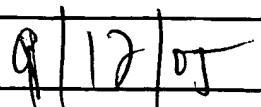


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. M122-2067		SERIAL NO. 10/624,340	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT: Brent A. McClure et al.			
					FILING DATE July 21, 2003		GROUP 2831	
U.S. PATENT DOCUMENTS								
Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate		
NH ↓ ↓ ↓ ↓ ↓ ↓ NH	AA	5,808,947	06/1999	Vaartstra				
	AB	6,359,295 B2	03/2002	Yang et al.				
	AC	6,598,802 B2	07/2003	Lizuka et al.				
	AD	6,627,462 B1	08/2003	Yang et al.				
	AE	6,664,186 B1	12/2003	Callegari et al.				
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	AG	2002/0109198 A1	08/2002	Yang et al.				
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FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country	Class	Subclass	Translation		
						Yes	No	
NH NH	AJ	KR 2002048433	05/2003	Lee, J.W.				
	AK	EP 1 508 906 A2	02/2005	Lee et al.				
	AL							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AM							
	AN							
	AO							
EXAMINER		DATE CONSIDERED  9/12/05						
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2067		SERIAL NO. 10/624,340	
 <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>				APPLICANT Brent A. McClure et al			
				FILING DATE July 21, 2003		GROUP 2831	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
NH	AA	2002/0142488	10/02	Hong, Suk-Kyoung			
NH	AB	6,403,156	06/02	Jang			
NH	AC	6,746,930	6/04	Yang			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AM							
AN							
AO							
AP							
AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
AR	Ritala et al, "Perfectly Conformal TiN and Al2O3 Films Deposited by Atomic Layer Deposition," Chemical Vapor Deposition, v. 5, No. 1, 1999, p. 7-9.						
AS							
EXAMINER	DATE CONSIDERED			9/17/05			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2067		SERIAL NO. 10/624,340	
 <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>					APPLICANT Brent A. McClure et al			
					FILING DATE July 21, 2003		GROUP 2831	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
NH	AA	09/653,156	Agarwal (as amended 12/2004)					
	AB							
	AC							
	AD							
	AE							
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country	Class	Subclass	Translation		
						Yes	No	
	AM							
	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AQ							
	AR							
EXAMINER				DATE CONSIDERED				
								
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

Form PTO-149		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2067		SERIAL NO. 10/624,340		
<div style="text-align: center;"> LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) </div>				APPLICANT Brent A. McClure et al				
				FILING DATE July 21, 2003		GROUP 2831		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
NH	AA	6,222,722	04/1999	Fukuzumi et al				
	AB	6,204,070	03/2001	Kim				
	AC	6,207,487	03/2001	Kim et al				
	AD	6,391,803	05/2002	Kim et al				
	AE	6,420,230	07/2002	Derderian				
	AF	6,281,543	08/2001	Al-Shareef et al				
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	AK	6,551,399	04/2003	Sneh et al				
NH	AL	6,780,704	08/2004	Rasijmakers				
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
NH	AM	KR 2002002157A	01/2002	Korea				
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
EXAMINER					DATE CONSIDERED 9/12/05			
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